

X-ray Magnetic Circular Dichroism Spectroscopy and Magnetic Imaging at SPring-8

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X-ray magnetic circular dichroism (XMCD) spectroscopy is a key technique to study the magnetic materials, offering the element specificity and the high detection sensitivity of magnetic moments. The XMCD technique can be combined with the state-of-the-art X-ray focusing optics such that scanning magnetic microscopy using a circularly-polarized X-ray nanoprobe will become possible. At SPring-8, we have developed XMCD spectroscopy and magnetic microscopy/imaging techniques in the soft and hard X-ray regions [1–4]. In this talk, we describe the current status of the instrumentation developments at the soft X-ray (BL25SU) and hard X-ray (BL39XU) beamlines dedicated to the XMCD study. These beamlines offer the capability of fast helicity switching of the circularly polarized X-ray beam with the high-sensitive lock-in detection of dichroic signals. For magnetic imaging, BL25SU is equipped with a Fresnel zone plate for a scanning soft-XMCD microscopy under strong magnetic fields by a unique combination with an 8-T-superconducting magnet [2, 3]. BL39XU is equipped with a Kirkpatrick-Baez mirror setup for scanning hard-XMCD microscopy with the spatial resolution of 100 nm [4]. We present some recent results including XMCD study of voltage-induced magnetic anisotropy in transition metal/MgO junctions [5, 6], time-resolved XMCD microscopy in a Co/Pt multilayer micro-disk to study the spin precession dynamics in the non-linear regime of ferromagnetic resonance [7], and three-dimensional observation of internal magnetic domains using scanning hard-X-ray magnetic microtomography [8].

References

- [1] - T. Nakamura and M. Suzuki, *J. Phys. Soc. Jpn.* **82**, 021006 (2013).
- [2] - Y. Kotani, Y. Senba, K. Toyoki, D. Billington, H. Okazaki, A. Yasui, W. Ueno, H. Ohashi, S. Hirose, Y. Shiratsuchi, and T. Nakamura, *J. Synchrotron Rad.* **25**, 1444 (2018).
- [3] - D. Billington, K. Toyoki, H. Okazaki, Y. Kotani, T. Fukagawa, T. Nishiuchi, S. Hirose, and T. Nakamura, *Phys. Rev. Mater.* **2**, 104413 (2018).
- [4] - M. Suzuki, N. Kawamura, M. Mizumaki, Y. Terada, T. Uruga, A. Fujiwara, H. Yamazaki, H. Yumoto, T. Koyama, Y. Senba, T. Takeuchi, H. Ohashi, N. Nariyama, K. Takeshita, H. Kimura, T. Matsushita, Y. Furukawa, T. Ohata, Y. Kondo, J. Ariake, J. Richter, P. Fons, O. Sekizawa, N. Ishiguro, M. Tada, S. Goto, M. Yamamoto, M. Takata, and T. Ishikawa, *J. Phys. Conf. Ser.* **430**, 012017 (2013).
- [5] - S. Miwa, M. Suzuki, M. Tsujikawa, K. Matsuda, T. Nozaki, K. Tanaka, T. Tsukahara, K. Nawaoka, M. Goto, Y. Kotani, T. Ohkubo, F. Bonell, E. Tamura, K. Hono, T. Nakamura, M. Shirai, S. Yuasa, and Y. Suzuki, *Nat Comm* **8**, 15848 (2017).
- [6] - S. Miwa, M. Suzuki, M. Tsujikawa, T. Nozaki, T. Nakamura, M. Shirai, S. Yuasa, and Y. Suzuki, *J. Phys. D: Appl. Phys.* **52**, 063001 (2019).
- [7] - N. Kikuchi, H. Osawa, M. Suzuki, and O. Kitakami, *IEEE Trans. Magn.* **54**, 6100106 (2018).
- [8] - M. Suzuki, K.-J. Kim, S. Kim, H. Yoshikawa, T. Tono, K. T. Yamada, T. Taniguchi, H. Mizuno, K. Oda, M. Ishibashi, Y. Hirata, T. Li, A. Tsukamoto, D. Chiba, and T. Ono, *Appl. Phys. Express* **11**, 036601 (2018).